Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination			
10/749,489	JWA, SEUNG	G HEE		
Examiner	Art Unit			
Lee Calvin	2818	20063/10020		

	SEARCHED				
Class	Subclass	Date	Examiner		
257	301-314	1/31/2005	CL		
438	257-267	#	#		
#	593, 594	#	#		
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Class	Subclass	Date	HED Examiner
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